Notice of References Cited Reexamination JOHANSSON ET AL. Examiner Prenell P. Jones Reexamination JOHANSSON ET AL. Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,850,965	02-2005	Allen, Arthur Douglas	709/203 .
	В	US-6,718,533	04-2004	Schneider et al.	717/100
	С	US-6,618,377	09-2003	Miriyala, Prasad	370/395.1
	D	US-6,590,928	07-2003	Haartsen, Jacobus Cornelis	375/134
	Е	US-6,735,448	05-2004	Krishnamurthy et al.	455/522
	F	US-6,751,200	06-2004	Larsson et al.	370/255
	G	US-2004/0196784	10-2004	Larsson et al.	370/228
	Н	US-2004/0095907	05-2004	Agee et al.	370/334
	ı	US-2001/0003191	06-2001	Kovacs et al.	709/226
	J	US-		·	
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т				·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
:	U	Haijun Luo et al; A topology-independent fair queueing model in ad hoc wireless networks Network Protocols, 2000. Proceedings. 2000 International Conference on, 14-17 Nov. 2000 Page(s):325 - 335			
	٧	Chang et al.; Routing in wireless/mobile ad-hoc via dynamic group contruction; Moble Networks and Application archives, Volume 5, Issue 1 (March 2000) table of contents Pages: 27 - 37			
	w	K. Y. Eng, M. J. Karol, M. Veeraraghavan, E. Ayanoglu, C. B. Woodworth, P. Pancha, R. A. Valenzuela; A wireless broadband ad-hoc ATM local-area network; February 1995, Wireless Networks, Volume 1 Issue 2, Pages: 161-174.			
	×	Ayyagari, D. et al; A unified approach to scheduling, access control and routing for ad-hoc wireless networks; Vehicular Technology Conference Proceedings, 2000. VTC 2000-Spring Tokyo. 2000 IEEE 51st Volume 1, 15-18 May 2000 Page(s):			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under